



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV _{DSS} /	R _{DS(ON)}	V _{GS(th)}	I _{D(ON)} (min)	Order Number / Package		
BV _{DGS}	(max)	(max)		TO-243AA*	Die [†]	
-100V	3.5Ω	-2.4V	-1.5A	TP2510N8	TP2510ND	

^{*} Same as SOT-89. Product supplied on 2000 piece carrier tape reels.

Features

- Low threshold -2.4V max.
- High input impedance
- Low input capacitance 125pF max.
- Fast switching speeds
- Low on resistance
- Free from secondary breakdown
- Low input and output leakage
- Complementary N- and P-channel devices

Applications

- ☐ Logic level interfaces ideal for TTL and CMOS
- Solid state relays
- Battery operated systems
- Photo voltaic drives
- Analog switches
- General purpose line drivers
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

^{*} Distance of 1.6 mm from case for 10 seconds.



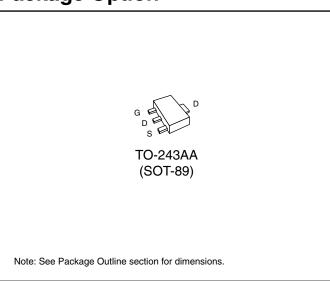
Where * = 2-week alpha date code

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired

Package Option



[†]MIL visual screening available.

Thermal Characteristics

Package	I _D (continuous)*	I _D (pulsed)	Power Dissipation @ T _A = 25°C	$ heta_{ extsf{jc}}$ °C/W	$ heta_{ja}$ °C/W	I _{DR} *	I _{DRM}
TO-243AA	-480mA	-2.5A	1.6W [†]	15	78 [†]	-480mA	-2.5A

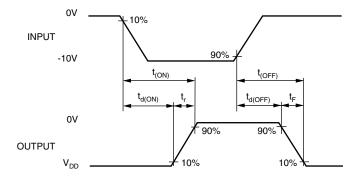
Electrical Characteristics (@ 25°C unless otherwise specified)

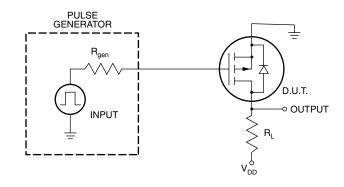
Symbol	Parameter	Min	Тур	Max	Unit	Conditions	
BV _{DSS}	Drain-to-Source Breakdown Voltage	-100			V	V _{GS} = 0V, I _D = -2.0mA	
V _{GS(th)}	Gate Threshold Voltage	-1.0		-2.4	V	$V_{GS} = V_{DS}$, $I_D = -1.0$ mA	
$\Delta V_{GS(th)}$	Change in V _{GS(th)} with Temperature			5.0	mV/°C	$V_{GS} = V_{DS}$, $I_D = -1.0$ mA	
I _{GSS}	Gate Body Leakage			-100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
I _{DSS}	Zero Gate Voltage Drain Current			-10	μА	V _{GS} = 0V, V _{DS} = Max Rating	
				-1.0	mA	$V_{GS} = 0V$, $V_{DS} = 0.8$ Max Rating $T_A = 125$ °C	
I _{D(ON)}	ON-State Drain Current	-0.4	-0.6		Α	V _{GS} = -5.0V, V _{DS} = -25V	
		-1.5	-2.5			$V_{GS} = -10V, V_{DS} = -25V$	
R _{DS(ON)}	Static Drain-to-Source ON-State Resistance		5.0	7.0	Ω	$V_{GS} = -5.0V, I_D = -250mA$	
			2.0	3.5		$V_{GS} = -10V, I_D = -0.75A$	
$\Delta R_{DS(ON)}$	Change in R _{DS(ON)} with Temperature			1.7	%/°C	$V_{GS} = -10V, I_D = -0.75A$	
G _{FS}	Forward Transconductance	300	360		m℧	$V_{DS} = -25V, I_{D} = -0.75A$	
C _{ISS}	Input Capacitance		80	125		$V_{GS} = 0V, V_{DS} = -25V$	
C _{oss}	Common Source Output Capacitance		40	70	pF	$v_{GS} = 0v$, $v_{DS} = -25v$ f = 1.0 MHz	
C _{RSS}	Reverse Transfer Capacitance		10	25		1 – 1.0 WH12	
t _{d(ON)}	Turn-ON Delay Time			10		V _{DD} = -25V,	
t _r	Rise Time			15			
t _{d(OFF)}	Turn-OFF Delay Time			20	ns	$I_D = -1.0A,$ $R_{GEN} = 25\Omega$	
t _f	Fall Time			15			
V _{SD}	Diode Forward Voltage Drop			-1.8	V	$V_{GS} = 0V, I_{SD} = -1.0A$	
t _{rr}	Reverse Recovery Time		300		ns	V _{GS} = 0V, I _{SD} = -1.0A	

Notes:

- 1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300µs pulse, 2% duty cycle.)
- 2. All A.C. parameters sample tested.

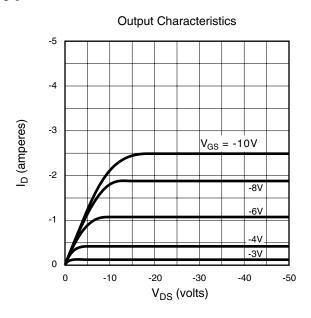
Switching Waveforms and Test Circuit

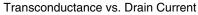


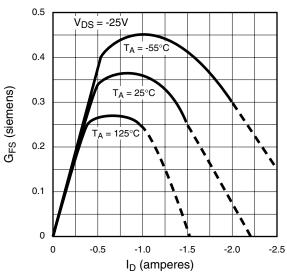


 $[\]begin{tabular}{l} \star I_D$ (continuous) is limited by max rated T_j. \\ t Mounted on FR5 board, 25mm x 25mm x 1.57mm. Significant P_D increase possible on ceramic substrate. \\ \end{tabular}$

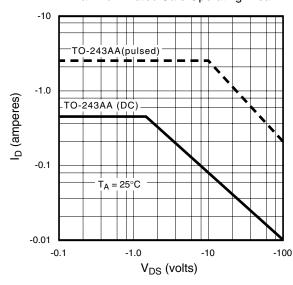
Typical Performance Curves



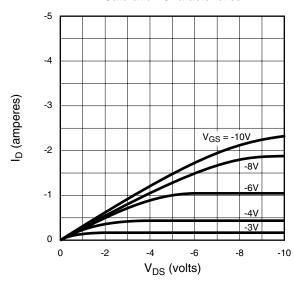




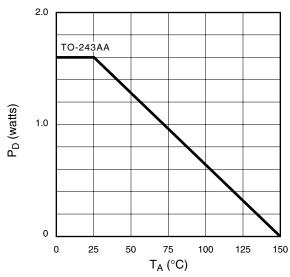
Maximum Rated Safe Operating Area



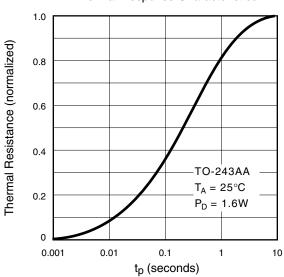
Saturation Characteristics



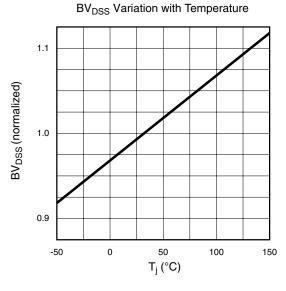
Power Dissipation vs. Ambient Temperature

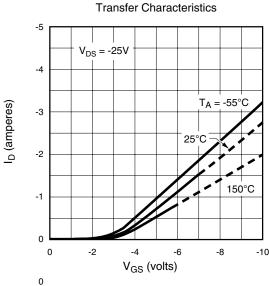


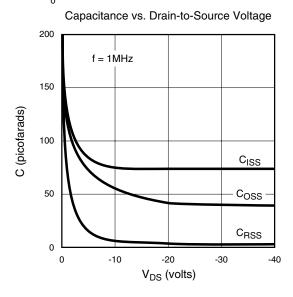
Thermal Response Characteristics

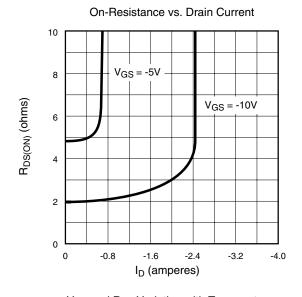


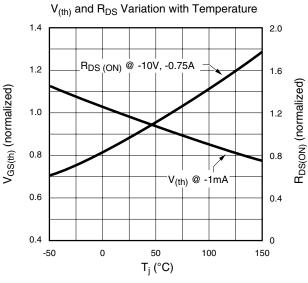
Typical Performance Curves

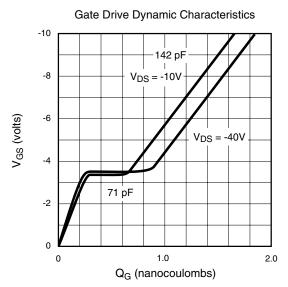












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